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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Group Art Unit: 2895
Examiner: Swapneel CHHAYA

In Re PATENT APPLICATION of:

Applicant(s): Takamitsu YAMANAKA)
U.S. Serial No.: 10/577,457)
U.S. Filing Date: April 27, 2006)
International Serial No.: PCT/JP2005/014208)
International Filing Date: August 3, 2005)
Priority Date Claimed: August 17, 2004)
For: SEMICONDUCTOR DEVICE)
AND ITS MANUFACTURING)
METHOD)
Attorney Reference: AI 409NP)

AMENDMENT

September 24, 2009

/Swapneel Chhaya/ 10/08/2009
Do not enter

Mail Stop AF
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Sir:

In response to the Examiner's Action mailed on June 24, 2009, please
amend the above-identified application as follows: